

Notice of References Cited

Application/Control No.

10/058,651

Applicant(s)/Patent Under

Reexamination

BLUMENAU ET AL.

Examiner

Kyung H Shin

Art Unit

2132

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U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|----|---|--|--------------------|----------------------------|--------------------|
| 62 | A | US-4,465,901 | 08-1984 | Best, Robert M. | 713/190 |
| | B | US-5,998,858 | 12-1999 | Little et al. | 257/678 |
| | C | US-5,007,083 | 04-1991 | Constant, James N. | 713/194 |
| | D | US-5,925,133 | 07-1999 | Buxton et al. | 713/323 |
| 62 | E | US-6,327,654 | 12-2001 | Oowaki et al. | 713/167 |
| | F | US-5,881,155 | 03-1999 | Rigal, Vincent | 380/44 |
| | G | US- | | | |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

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